





AGENCY CERTIFIED/PACKAGE	DUAL CHANNEL			QUAD CHANNEL		
	CTR (%)					
VDE, UL, CSA, BSI, FIMKO	20 to 300	100 to 500	50 to 400	20 to 300	100 to 500	50 to 400
DIP-8	ILD1-X001	ILD2-X001	ILD5-X001	-	-	-
DIP-8, 400 mil, option 6	-	ILD2-X016	-	-	-	-
SMD-8, option 7	-	ILD2-X017	-	-	-	-
SMD-8, option 9	ILD1-X019T	-	-	-	-	-
DIP-16	-	-	-	-	ILQ2-X001	-
DIP-16, 400 mil, option 6	-	-	-	-	ILQ2-X016	-
SMD-16, option 7	-	-	-	-	ILQ2-X017T <sup>(1)</sup>	-

**Notes**

- Additional options may be possible, please contact sales office.
- <sup>(1)</sup> Also available in tubes; do not put T on end.

ABSOLUTE MAXIMUM RATINGS ( $T_{amb} = 25\text{ }^{\circ}\text{C}$ , unless otherwise specified)					
PARAMETER	TEST CONDITION	PART	SYMBOL	VALUE	UNIT
<b>INPUT</b>					
Reverse voltage			$V_R$	6	V
Forward current			$I_F$	60	mA
Surge current			$I_{FSM}$	2.5	A
Power dissipation			$P_{diss}$	100	mW
Derate linearly from 25 °C				1.3	mW/°C
<b>OUTPUT</b>					
Collector emitter reverse voltage		ILD1	$V_{CEO}$	50	V
		ILQ1	$V_{CEO}$	50	V
		ILD2	$V_{CEO}$	70	V
		ILQ2	$V_{CEO}$	70	V
		ILD5	$V_{CEO}$	70	V
		ILQ5	$V_{CEO}$	70	V
Collector current	$t < 1\text{ ms}$		$I_C$	50	mA
			$I_C$	400	mA
Power dissipation			$P_{diss}$	200	mW
Derate linearly from 25 °C				2.6	mW/°C
<b>COUPLER</b>					
Isolation test voltage between emitter and detector			$V_{ISO}$	5300	$V_{RMS}$
Creepage distance				$\geq 7$	mm
Clearance distance				$\geq 7$	mm
Isolation resistance	$V_{IO} = 500\text{ V}, T_{amb} = 25\text{ }^{\circ}\text{C}$		$R_{IO}$	$\geq 10^{12}$	$\Omega$
	$V_{IO} = 500\text{ V}, T_{amb} = 100\text{ }^{\circ}\text{C}$		$R_{IO}$	$\geq 10^{11}$	
Package power dissipation			$P_{tot}$	250	mW
Derate linearly from 25 °C				3.3	mW/°C
Storage temperature			$T_{stg}$	- 40 to + 150	°C
Operating temperature			$T_{amb}$	- 40 to + 100	°C
Junction temperature			$T_j$	100	°C
Soldering temperature <sup>(2)</sup>	2 mm from case bottom		$T_{sld}$	260	°C

**Notes**

- Stresses in excess of the absolute maximum ratings can cause permanent damage to the device. Functional operation of the device is not implied at these or any other conditions in excess of those given in the operational sections of this document. Exposure to absolute maximum ratings for extended periods of the time can adversely affect reliability.
- <sup>(1)</sup> Refer to reflow profile for soldering conditions for surface mounted devices (SMD). Refer to wave profile for soldering conditions for through hole devices (DIP).



<b>ELECTRICAL CHARACTERISTICS</b> ( $T_{amb} = 25\text{ }^{\circ}\text{C}$ , unless otherwise specified)						
PARAMETER	TEST CONDITION	SYMBOL	MIN.	TYP.	MAX.	UNIT
<b>INPUT</b>						
Forward voltage	$I_F = 60\text{ mA}$	$V_F$		1.25	1.65	V
Reverse current	$V_R = 6\text{ V}$	$I_R$		0.01	10	$\mu\text{A}$
Capacitance	$V_R = 0\text{ V}$ , $f = 1\text{ MHz}$	$C_O$		25		pF
Thermal resistance, junction to lead		$T_{thJL}$		750		K/W
<b>OUTPUT</b>						
Collector emitter capacitance	$V_{CE} = 5\text{ V}$ , $f = 1\text{ MHz}$	$C_{CE}$		6.8		pF
Collector emitter leakage current	$V_{VCE} = 10\text{ V}$	$I_{CEO}$		5	50	nA
Saturation voltage, collector emitter	$I_C = 1\text{ mA}$ , $I_B = 20\text{ }\mu\text{A}$	$V_{CESAT}$		0.25	0.4	V
DC forward current gain	$V_{CE} = 10\text{ V}$ , $I_B = 20\text{ }\mu\text{A}$	$h_{FE}$	200	650	1800	
DC forward current gain saturated	$V_{CE} = 0.4\text{ V}$ , $I_B = 20\text{ }\mu\text{A}$	$h_{FEsat}$	120	400	600	
Thermal resistance, junction to lead		$R_{thjL}$		500		K/W
<b>COUPLER</b>						
Capacitance (input to output)	$V_{IO} = 0\text{ V}$ , $f = 1\text{ MHz}$	$C_{IO}$		0.8		pF

**Note**

- Minimum and maximum values are testing requirements. Typical values are characteristics of the device and are the result of engineering evaluation. Typical values are for information only and are not part of the testing requirements.

<b>CURRENT TRANSFER RATIO</b> ( $T_{amb} = 25\text{ }^{\circ}\text{C}$ , unless otherwise specified)							
PARAMETER	TEST CONDITION	PART	SYMBOL	MIN.	TYP.	MAX.	UNIT
$I_C/I_F$ (collector emitter saturated)	$I_F = 10\text{ mA}$ , $V_{CE} = 0.4\text{ V}$	ILD1	$CTR_{CEsat}$		75		%
		ILQ1	$CTR_{CEsat}$		75		%
		ILD2	$CTR_{CEsat}$		170		%
		ILQ2	$CTR_{CEsat}$		170		%
		ILD5	$CTR_{CEsat}$		100		%
		ILQ5	$CTR_{CEsat}$		100		%
	$I_F = 10\text{ mA}$ , $V_{CE} = 10\text{ V}$	ILD1	$CTR_{CE}$	20	80	300	%
		ILQ1	$CTR_{CE}$	20	80	300	%
		ILD2	$CTR_{CE}$	100	200	500	%
		ILQ2	$CTR_{CE}$	100	200	500	%
		ILD5	$CTR_{CE}$	50	130	400	%
		ILQ5	$CTR_{CE}$	50	130	400	%

SAFETY AND INSULATION RATINGS						
PARAMETER	TEST CONDITION	SYMBOL	MIN.	TYP.	MAX.	UNIT
Isolation test voltage between emitter and detector		$V_{ISO}$	5300			$V_{RMS}$
Isolation resistance	$V_{IO} = 500\text{ V}, T_{amb} = 25\text{ }^{\circ}\text{C}$	$R_{IO}$	$10^{12}$			$\Omega$
	$V_{IO} = 500\text{ V}, T_{amb} = 100\text{ }^{\circ}\text{C}$		$10^{11}$			
Climatic classification (according to IEC 68 part 1)				55/100/21		
Comparative tracking index		CTI	175			
Rated impulse voltage		$V_{IOTM}$			10	kV
Maximum working voltage	Recurring peak voltage	$V_{IORM}$			890	V
Forward current		$I_{SI}$			275	mA
Power dissipation		$P_{SO}$			400	mW
Safety temperature		$T_{SI}$			175	$^{\circ}\text{C}$
Creepage distance			7.0			mm
Clearance distance			7.0			mm
Insulation distance	per IEC 60950 2.10.5.1		0.4			mm

**Note**

- According to DIN EN 60747-5-2 (VDE 0884) (see figure 2). These optocouplers are suitable for “safety electrical insulation” only within the safety ratings. Compliance with the safety ratings shall be ensured by means of suitable protective circuits.

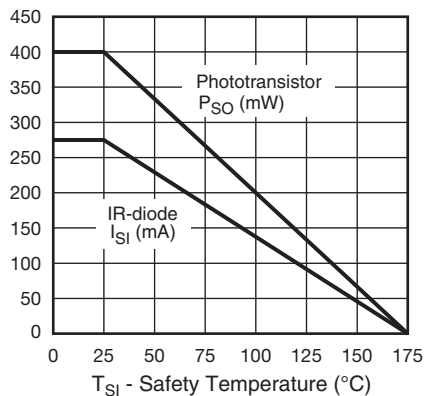


Fig. 1 - Derating Diagram

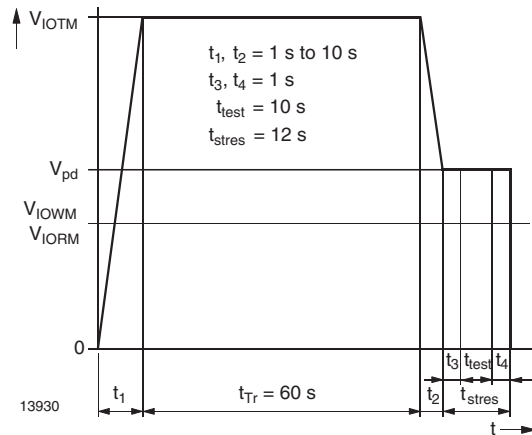


Fig. 2 - Test Pulse Diagram for Sample Test according to DIN EN 60747-5-2 (VDE 0884); IEC 60747-5-5



SWITCHING CHARACTERISTICS (T <sub>amb</sub> = 25 °C, unless otherwise specified)							
PARAMETER	TEST CONDITION	PART	SYMBOL	MIN.	TYP.	MAX.	UNIT
<b>NON-SATURATED</b>							
Current	V <sub>CE</sub> = 5 V, R <sub>L</sub> = 75 Ω, 50 % of V <sub>PP</sub>	ILD1	I <sub>F</sub>		20		mA
		ILQ1	I <sub>F</sub>		20		mA
		ILD2	I <sub>F</sub>		5		mA
		ILQ2	I <sub>F</sub>		5		mA
		ILD5	I <sub>F</sub>		10		mA
		ILQ5	I <sub>F</sub>		10		mA
Delay	V <sub>CE</sub> = 5 V, R <sub>L</sub> = 75 Ω, 50 % of V <sub>PP</sub>	ILD1	t <sub>D</sub>		0.8		μs
		ILQ1	t <sub>D</sub>		0.8		μs
		ILD2	t <sub>D</sub>		1.7		μs
		ILQ2	t <sub>D</sub>		1.7		μs
		ILD5	t <sub>D</sub>		1.7		μs
		ILQ5	t <sub>D</sub>		1.7		μs
Rise time	V <sub>CE</sub> = 5 V, R <sub>L</sub> = 75 Ω, 50 % of V <sub>PP</sub>	ILD1	t <sub>r</sub>		1.9		μs
		ILQ1	t <sub>r</sub>		1.9		μs
		ILD2	t <sub>r</sub>		2.6		μs
		ILQ2	t <sub>r</sub>		2.6		μs
		ILD5	t <sub>r</sub>		2.6		μs
		ILQ5	t <sub>r</sub>		2.6		μs
Storage	V <sub>CE</sub> = 5 V, R <sub>L</sub> = 75 Ω, 50 % of V <sub>PP</sub>	ILD1	t <sub>s</sub>		0.2		μs
		ILQ1	t <sub>s</sub>		0.2		μs
		ILD2	t <sub>s</sub>		0.4		μs
		ILQ2	t <sub>s</sub>		0.4		μs
		ILD5	t <sub>s</sub>		0.4		μs
		ILQ5	t <sub>s</sub>		0.4		μs
Fall time	V <sub>CE</sub> = 5 V, R <sub>L</sub> = 75 Ω, 50 % of V <sub>PP</sub>	ILD1	t <sub>f</sub>		1.4		μs
		ILQ1	t <sub>f</sub>		1.4		μs
		ILD2	t <sub>f</sub>		2.2		μs
		ILQ2	t <sub>f</sub>		2.2		μs
		ILD5	t <sub>f</sub>		2.2		μs
		ILQ5	t <sub>f</sub>		2.2		μs
Propagation H to L	V <sub>CE</sub> = 5 V, R <sub>L</sub> = 75 Ω, 50 % of V <sub>PP</sub>	ILD1	t <sub>PHL</sub>		0.7		μs
		ILQ1	t <sub>PHL</sub>		0.7		μs
		ILD2	t <sub>PHL</sub>		1.2		μs
		ILQ2	t <sub>PHL</sub>		1.2		μs
		ILD5	t <sub>PHL</sub>		1.1		μs
		ILQ5	t <sub>PHL</sub>		1.1		μs
Propagation L to H	V <sub>CE</sub> = 5 V, R <sub>L</sub> = 75 Ω, 50 % of V <sub>PP</sub>	ILD1	t <sub>PLH</sub>		1.4		μs
		ILQ1	t <sub>PLH</sub>		1.4		μs
		ILD2	t <sub>PLH</sub>		2.3		μs
		ILQ2	t <sub>PLH</sub>		2.3		μs
		ILD5	t <sub>PLH</sub>		2.5		μs
		ILQ5	t <sub>PLH</sub>		2.5		μs



SWITCHING CHARACTERISTICS ( $T_{amb} = 25\text{ }^{\circ}\text{C}$ , unless otherwise specified)							
PARAMETER	TEST CONDITION	PART	SYMBOL	MIN.	TYP.	MAX.	UNIT
<b>SATURATED</b>							
Current	$V_{CE} = 0.4\text{ V}$ , $R_L = 1\text{ k}\Omega$ , $V_{CC} = 5\text{ V}$ , $V_{TH} = 1.5\text{ V}$	ILD1	$I_F$		20		mA
		ILQ1	$I_F$		20		mA
		ILD2	$I_F$		5		mA
		ILQ2	$I_F$		5		mA
		ILD5	$I_F$		10		mA
		ILQ5	$I_F$		10		mA
Delay	$V_{CE} = 0.4\text{ V}$ , $R_L = 1\text{ k}\Omega$ , $V_{CC} = 5\text{ V}$ , $V_{TH} = 1.5\text{ V}$	ILD1	$t_D$		0.8		$\mu\text{s}$
		ILQ1	$t_D$		0.8		$\mu\text{s}$
		ILD2	$t_D$		1		$\mu\text{s}$
		ILQ2	$t_D$		1		$\mu\text{s}$
		ILD5	$t_D$		1.7		$\mu\text{s}$
		ILQ5	$t_D$		1.7		$\mu\text{s}$
Rise time	$V_{CE} = 0.4\text{ V}$ , $R_L = 1\text{ k}\Omega$ , $V_{CC} = 5\text{ V}$ , $V_{TH} = 1.5\text{ V}$	ILD1	$t_r$		1.2		$\mu\text{s}$
		ILQ1	$t_r$		1.2		$\mu\text{s}$
		ILD2	$t_r$		2		$\mu\text{s}$
		ILQ2	$t_r$		2		$\mu\text{s}$
		ILD5	$t_r$		7		$\mu\text{s}$
		ILQ5	$t_r$		7		$\mu\text{s}$
Storage	$V_{CE} = 0.4\text{ V}$ , $R_L = 1\text{ k}\Omega$ , $V_{CC} = 5\text{ V}$ , $V_{TH} = 1.5\text{ V}$	ILD1	$t_s$		7.4		$\mu\text{s}$
		ILQ1	$t_s$		7.4		$\mu\text{s}$
		ILD2	$t_s$		5.4		$\mu\text{s}$
		ILQ2	$t_s$		5.4		$\mu\text{s}$
		ILD5	$t_s$		4.6		$\mu\text{s}$
		ILQ5	$t_s$		4.6		$\mu\text{s}$
Fall time	$V_{CE} = 0.4\text{ V}$ , $R_L = 1\text{ k}\Omega$ , $V_{CC} = 5\text{ V}$ , $V_{TH} = 1.5\text{ V}$	ILD1	$t_f$		7.6		$\mu\text{s}$
		ILQ1	$t_f$		7.6		$\mu\text{s}$
		ILD2	$t_f$		13.5		$\mu\text{s}$
		ILQ2	$t_f$		13.5		$\mu\text{s}$
		ILD5	$t_f$		20		$\mu\text{s}$
		ILQ5	$t_f$		20		$\mu\text{s}$
Propagation H to L	$V_{CE} = 0.4\text{ V}$ , $R_L = 1\text{ k}\Omega$ , $V_{CC} = 5\text{ V}$ , $V_{TH} = 1.5\text{ V}$	ILD1	$t_{PHL}$		1.6		$\mu\text{s}$
		ILQ1	$t_{PHL}$		1.6		$\mu\text{s}$
		ILD2	$t_{PHL}$		5.4		$\mu\text{s}$
		ILQ2	$t_{PHL}$		5.4		$\mu\text{s}$
		ILD5	$t_{PHL}$		2.6		$\mu\text{s}$
		ILQ5	$t_{PHL}$		2.6		$\mu\text{s}$
Propagation L to H	$V_{CE} = 0.4\text{ V}$ , $R_L = 1\text{ k}\Omega$ , $V_{CC} = 5\text{ V}$ , $V_{TH} = 1.5\text{ V}$	ILD1	$t_{PLH}$		8.6		$\mu\text{s}$
		ILQ1	$t_{PLH}$		8.6		$\mu\text{s}$
		ILD2	$t_{PLH}$		7.4		$\mu\text{s}$
		ILQ2	$t_{PLH}$		7.4		$\mu\text{s}$
		ILD5	$t_{PLH}$		7.2		$\mu\text{s}$
		ILQ5	$t_{PLH}$		7.2		$\mu\text{s}$

<b>COMMON MODE TRANSIENT IMMUNITY</b> ( $T_{amb} = 25\text{ }^{\circ}\text{C}$ , unless otherwise specified)						
PARAMETER	TEST CONDITION	SYMBOL	MIN.	TYP.	MAX.	UNIT
Common mode rejection, output high	$V_{CM} = 50\text{ V}_{P-P}$ , $R_L = 1\text{ k}\Omega$ , $I_F = 0\text{ mA}$	$CM_H$		5000		$\text{V}/\mu\text{s}$
Common mode rejection, output low	$V_{CM} = 50\text{ V}_{P-P}$ , $R_L = 1\text{ k}\Omega$ , $I_F = 10\text{ mA}$	$CM_L$		5000		$\text{V}/\mu\text{s}$
Common mode coupling capacitance		$C_{CM}$		0.01		$\text{pF}$

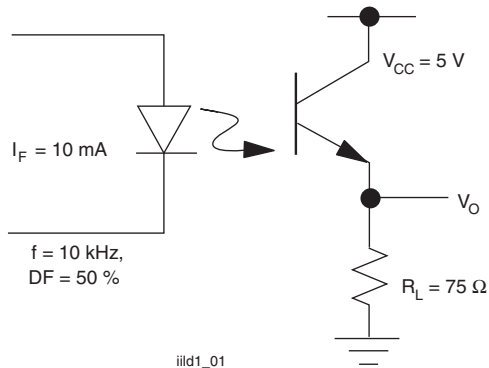
**TYPICAL CHARACTERISTICS** ( $T_{amb} = 25\text{ }^{\circ}\text{C}$ , unless otherwise specified)


Fig. 3 - Non-Saturated Switching Schematic

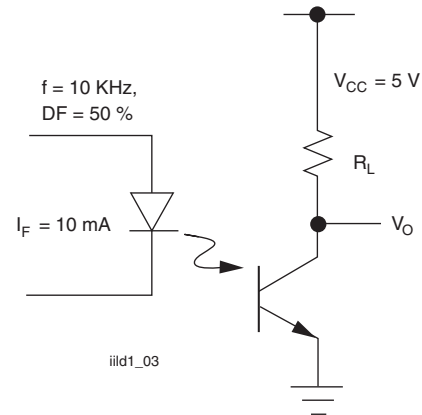


Fig. 5 - Saturated Switching Schematic

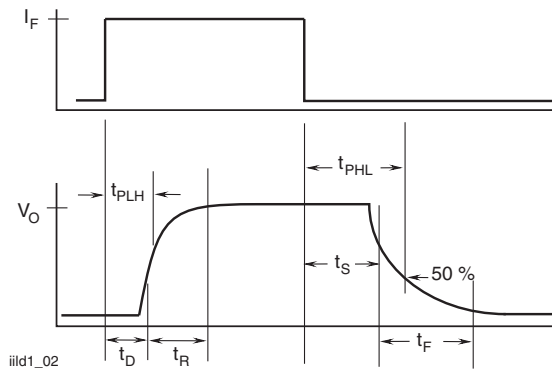


Fig. 4 - Non-Saturated Switching Timing

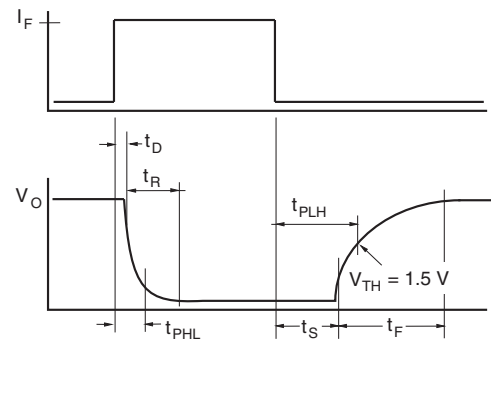


Fig. 6 - Saturated Switching Timing

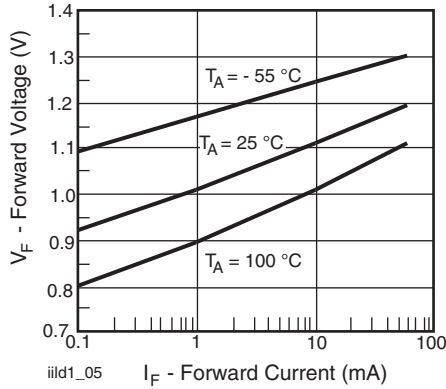


Fig. 7 - Normalized Non-Saturated and Saturated CTR vs. LED Current

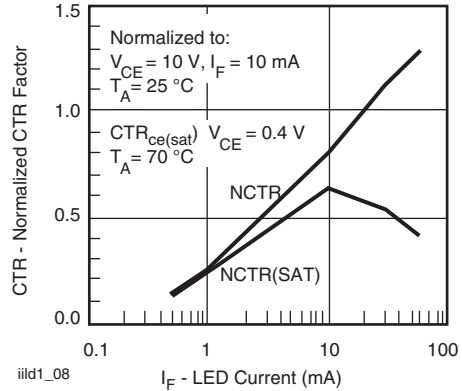


Fig. 10 - Normalized Non-Saturated and Saturated CTR vs. LED Current

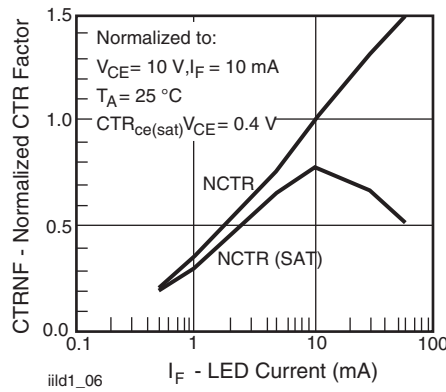


Fig. 8 - Normalized Non-Saturated and Saturated CTR vs. LED Current

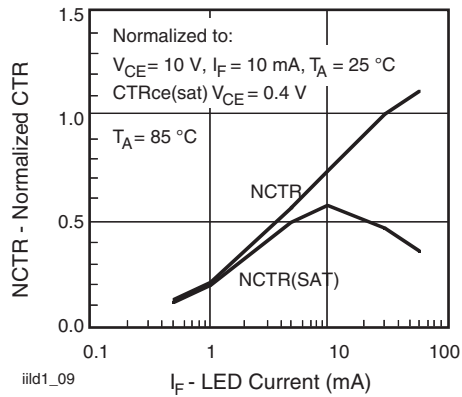


Fig. 11 - Normalized Non-Saturated and Saturated CTR vs. LED Current

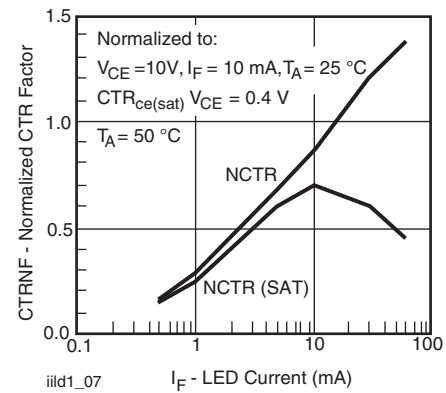


Fig. 9 - Normalized Non-Saturated and Saturated CTR vs. LED Current

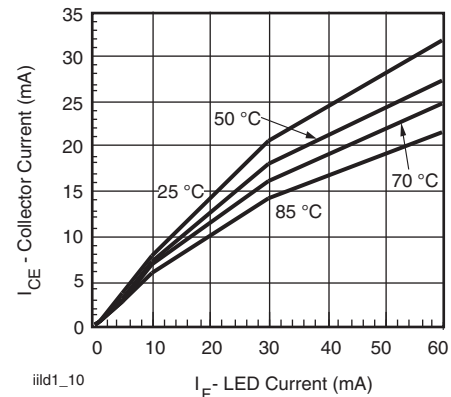


Fig. 12 - Collector Emitter Current vs. Temperature and LED Current



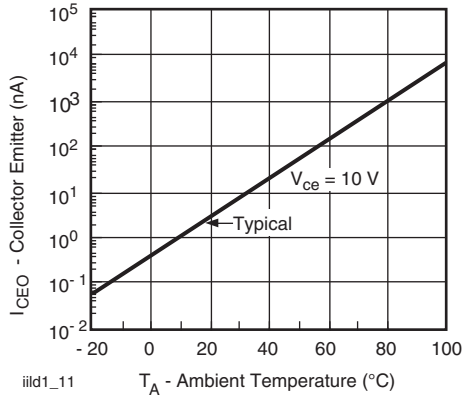


Fig. 13 - Collector Emitter Leakage Current vs. Temperature

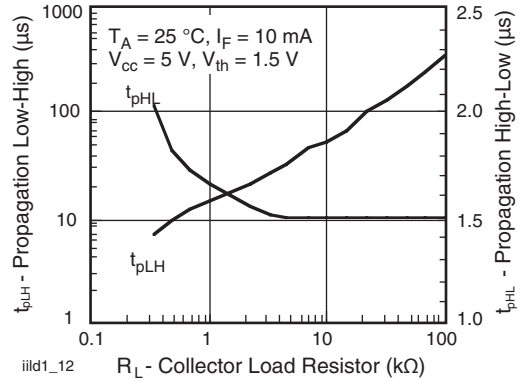
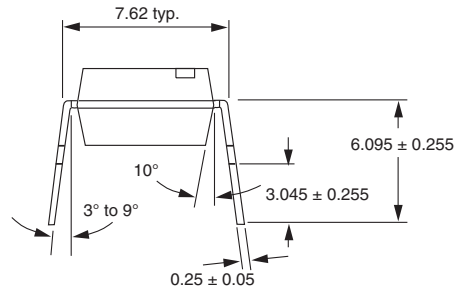
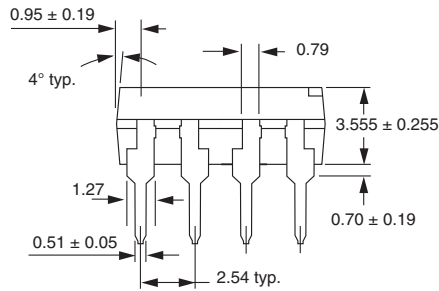
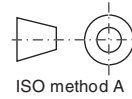
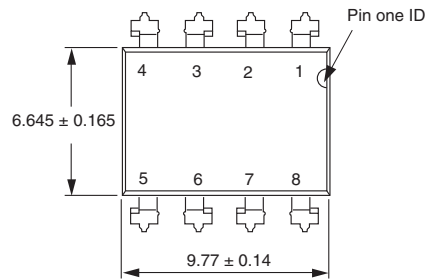


Fig. 14 - Propagation Delay vs. Collector Load Resistor

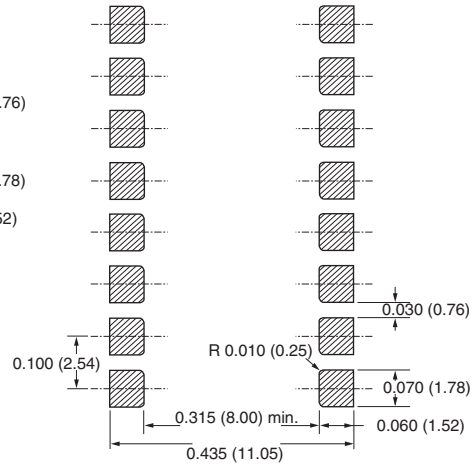
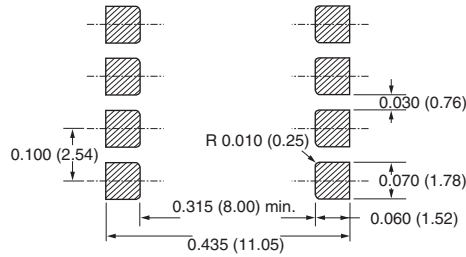
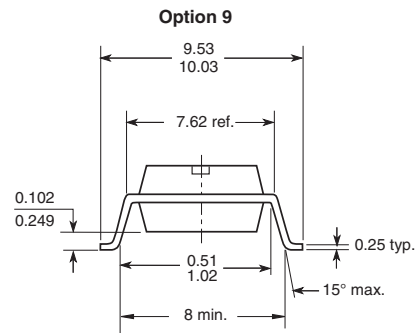
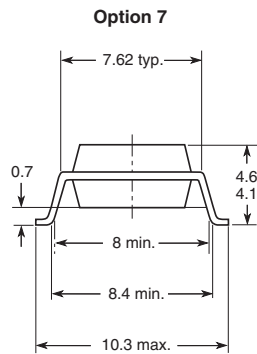
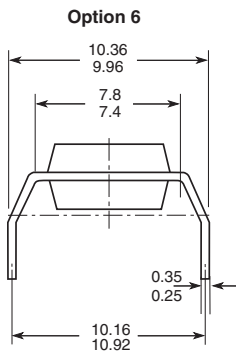
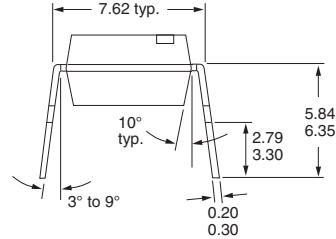
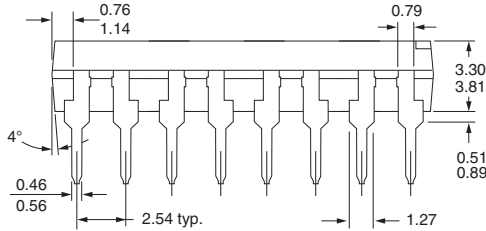
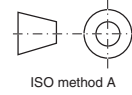
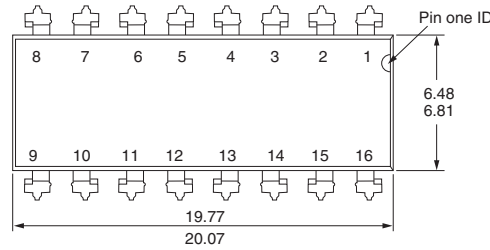
## PACKAGE DIMENSIONS in millimeters



i178006

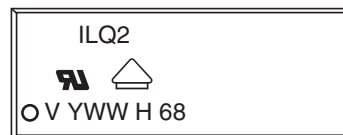
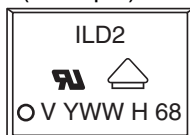


### PACKAGE DIMENSIONS in millimeters



18450-9

### PACKAGE MARKING (example)



### Notes

- Only option 1 and 7 reflected in the package marking.
- The VDE logo is only marked on option 1 parts.
- Tape and reel suffix (T) is not part of the package marking.



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